Deep Learning-Based Computer Vision: Technologies and Applications

Guest Editors:

Dr. Chao Ren
College of Electronics and Information Engineering, Sichuan University, Chengdu 610065, China

Dr. Yuanzhouhan Cao
School of Computer and Information Techology, Beijing Jiaotong University, Beijing 100044, China

Dr. Tao Li
School of Electrical Engineering and Electronic Information, Xihua University, Chengdu 610039, China

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Message from the Guest Editors

Research areas of the Special Issue may include (but are not limited to) the following: deep learning; computer vision; object detection; image classification; semantic segmentation; image generation; pose estimation; image reconstruction; image/video restoration; image/video enhancement; etc. We look forward to receiving your contributions.

- deep learning
- computer vision
- object detection
- image classification
- semantic segmentation
- image generation
- pose estimation
- image reconstruction
- image/video restoration
- image/video enhancement

Welcome to **contribute**.

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Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and Telecommunications,
Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

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